# **UFS Series N-Channel IGBT** with Anti-Parallel Hyperfast Diode

40 A, 600 V

# HGTG20N60B3D

The HGTG20N60B3D is a MOS gated high voltage switching device combining the best features of MOSFETs and bipolar transistors. The device has the high input impedance of a MOSFET and the low on-state conduction loss of a bipolar transistor. The much lower on-state voltage drop varies only moderately between 25°C and 150°C. The diode used in anti-parallel with the IGBT is the RHRP3060.

The IGBT is ideal for many high voltage switching applications operating at moderate frequencies where low conduction losses are essential.

Formerly developmental type TA49016.

## Features

- 40 A, 600 V at  $T_C = 25^{\circ}C$
- THIS DEVICE PLEASENTATIVE PLEASENTATIVE PLEASENTATIVE FOR FRESENTATIVE PLEASENTATIVE P • Typical Fall Time 140 ns at 150°C
- Short Circuit Rated
- Low Conduction Loss
- Hyperfast Anti-Parallel Diode
- This is a Pb–Free Device

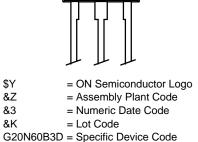


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<sup>Е</sup>с<sub>G</sub> COLLECTOR (BOTTOM SIDE METAL) TO-247-3LD SHORT LEAD CASE 340CK JEDEC STYLE MARKING DIAGRAM \$Y&Z&3&K G20N60B3D



#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 7 of this data sheet.

#### **ABSOLUTE MAXIMUM RATINGS** (T<sub>C</sub> = $25^{\circ}$ C unless otherwise specified)

Parameter	Symbol	HGTG20N60B3D	Unit
Collector to Emitter Voltage	BV <sub>CES</sub>	600	V
Collector to Gate Voltage, $R_{GE}$ = 1 M $\Omega$	BV <sub>CGR</sub>	600	V
Collector Current Continuous At $T_C = 25^{\circ}C$ At $T_C = 110^{\circ}C$	I <sub>C25</sub> I <sub>C110</sub>	40 20	A A
Average Diode Forward Current at 110°C	I <sub>(AVG)</sub>	20	А
Collector Current Pulsed (Note 1)	I <sub>CM</sub>	160	A
Gate to Emitter Voltage Continuous	V <sub>GES</sub>	±20	V
Gate to Emitter Voltage Pulsed	V <sub>GEM</sub>	±30	V
Switching Safe Operating Area at $T_C = 150^{\circ}C$	SSOA	30 A at 600 V	
Power Dissipation Total at $T_C = 25^{\circ}C$	PD	165	W
Power Dissipation Derating $T_C > 25^{\circ}C$		1.32	W/°C
Operating and Storage Junction Temperature Range	TJ, T <sub>STG</sub>	-40 to 150	°C
Maximum Lead Temperature for Soldering	ΤL	260	°C
Short Circuit Withstand Time (Note 2) at $V_{GE}$ = 15 V	tsc	4	μs
Short Circuit Withstand Time (Note 2) at $V_{GE} = 10 V$	tsc	10	μs

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
Repetitive Rating: Pulse width limited by maximum junction temperature.
V<sub>CE</sub> = 360 V, T<sub>C</sub> = 125°C, R<sub>G</sub> = 25 Ω

ELECTRICAL CHARACTERISTICS (T<sub>C</sub> = 25°C unless otherwise specified)

# ELECTRICAL CHARACTERISTICS (T<sub>C</sub> = 25°C unless otherwise specified)

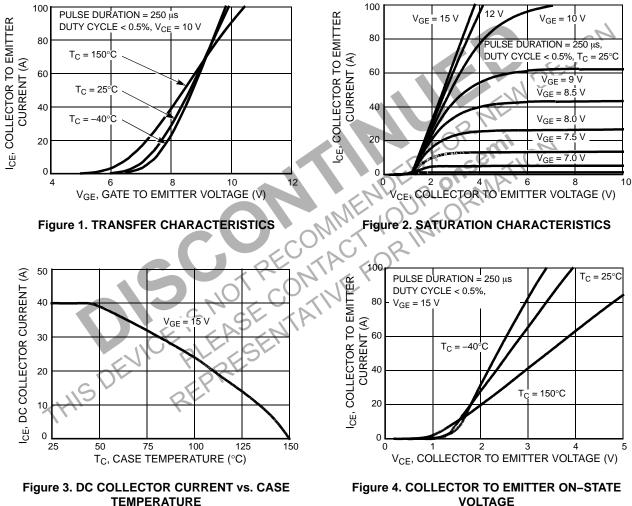
Parameter	Symbol	Test Condit	ion	Min	Тур	Max	Unit
Collector to Emitter Breakdown Voltage	BV <sub>CES</sub>	$I_{C} = 250 \ \mu A, \ V_{GE} = 0 \ V$	R	600	-	-	V
Collector to Emitter Leakage Current	ICES	V <sub>CE</sub> = BV <sub>CES</sub>	T <sub>C</sub> = 25°C	-	-	250	μΑ
	$\overline{)}$	CONTE	T <sub>C</sub> = 150°C	-	-	2.0	mA
Collector to Emitter Saturation Voltage	V <sub>CE(SAT)</sub>	I <sub>C</sub> = I <sub>C110</sub> , V <sub>GE</sub> = 15 V	$T_C = 25^{\circ}C$	-	1.8	2.0	V
	-AS	NIM	T <sub>C</sub> = 150°C	-	2.1	2.5	V
Gate to Emitter Threshold Voltage	V <sub>GE</sub> (TH)	lc = 250 μA, V <sub>CE</sub> = V <sub>GE</sub>		3.0	5.0	6.0	V
Gate to Emitter Leakage Current	IGES	$V_{GE} = \pm 20 \text{ V}$		-	-	±100	nA
Switching SOA	SSOA	$ \begin{array}{l} A \\ R_{G} = 150^{\circ}\text{C}, \ V_{GE} = 15 \ \text{V}, \\ R_{G} = 10 \ \Omega, \ L = 45 \ \mu\text{H} \\ \end{array} \\ \begin{array}{l} V_{CE} = 480 \ \text{V} \\ V_{CE} = 600 \ \text{V} \\ \end{array} $	100	-	-	А	
THIC K			V <sub>CE</sub> = 600 V	30	-	-	А
Gate to Emitter Plateau Voltage	V <sub>GEP</sub>	$I_{C} = I_{C110}, V_{CE} = 0.5 \text{ BV}_{CES}$		-	8.0	-	V
On-State Gate Charge		$I_{C} = I_{C_{110}},$	V <sub>GE</sub> = 15 V	-	80	105	nC
		$V_{GE} = 20 V$	-	105	135	nC	
Current Turn-On Delay Time	t <sub>d(ON)</sub>	$T_{C} = 150^{\circ}C,$ $I_{CE} = I_{C110},$ $V_{CE} = 0.8 \text{ BV}_{CES},$ $V_{GE} = 15 \text{ V},$ $R_{G} = 10 \Omega,$ $L = 100 \mu \text{H}$		-	25	-	ns
Current Rise Time	t <sub>rl</sub>			-	20	-	ns
Current Turn–Off Delay Time	t <sub>d(OFF)</sub> I			-	220	275	ns
Current Fall Time	t <sub>fl</sub>			-	140	175	ns
Turn–On Energy	E <sub>ON</sub>			-	475	-	μJ
Turn–Off Energy (Note 3)	E <sub>OFF</sub>			-	1050	-	μJ
Diode Forward Voltage	V <sub>EC</sub>	I <sub>EC</sub> = 20 A		-	1.5	1.9	V
Diode Reverse Recovery Time $t_{rr}$ $I_{EC} = 20$ A		$I_{EC} = 20 \text{ A}, \text{ d}I_{EC}/\text{d}t = 100$	A/µs	-	-	55	ns
		$I_{EC} = 1 \text{ A}, \ dI_{EC}/dt = 100 \text{ A}$	/μs	-	-	45	ns

#### ELECTRICAL CHARACTERISTICS (T<sub>C</sub> = 25°C unless otherwise specified) (continued)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Thermal Resistance	$R_{\thetaJC}$	IGBT	-	-	0.76	°C/W
		Diode	-	_	1.2	°C/W

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

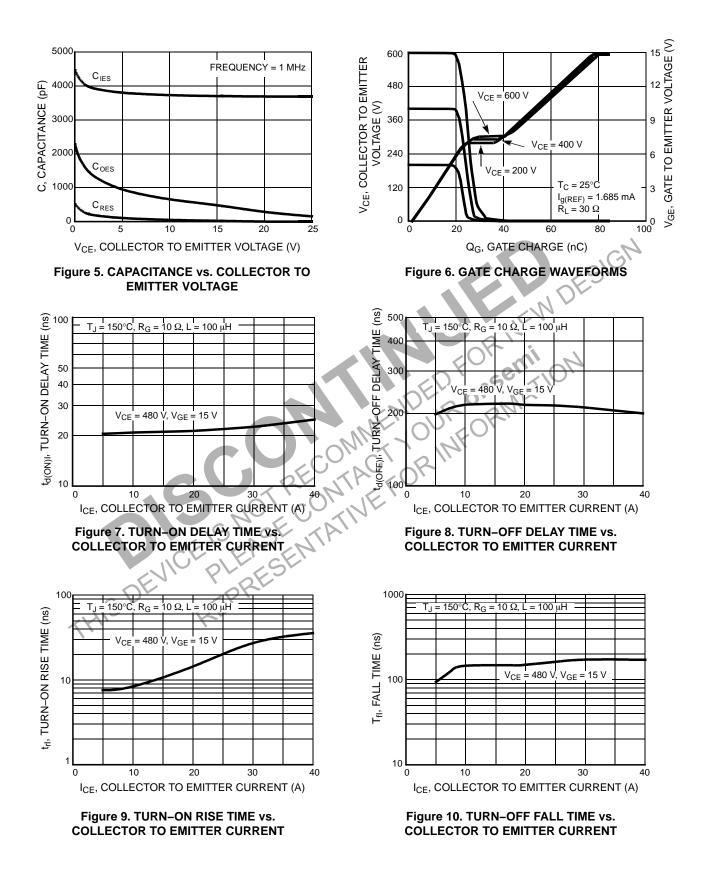
3. Turn-Off Energy Loss (EOFF) is defined as the integral of the instantaneous power loss starting at the trailing edge of the input pulse and ending at the point where the collector current equals zero (I<sub>CE</sub> = 0 A) The HGTG20N60B3D was tested per JEDEC standard No. 24-1 Method for Measurement of Power Device Turn-Off Switching Loss. This test method produces the true total Turn-Off Energy Loss. Turn-On losses include diode losses.



#### **TYPICAL PERFORMANCE CURVES**

VOLTAGE

### TYPICAL PERFORMANCE CURVES (continued)



#### TYPICAL PERFORMANCE CURVES (continued)

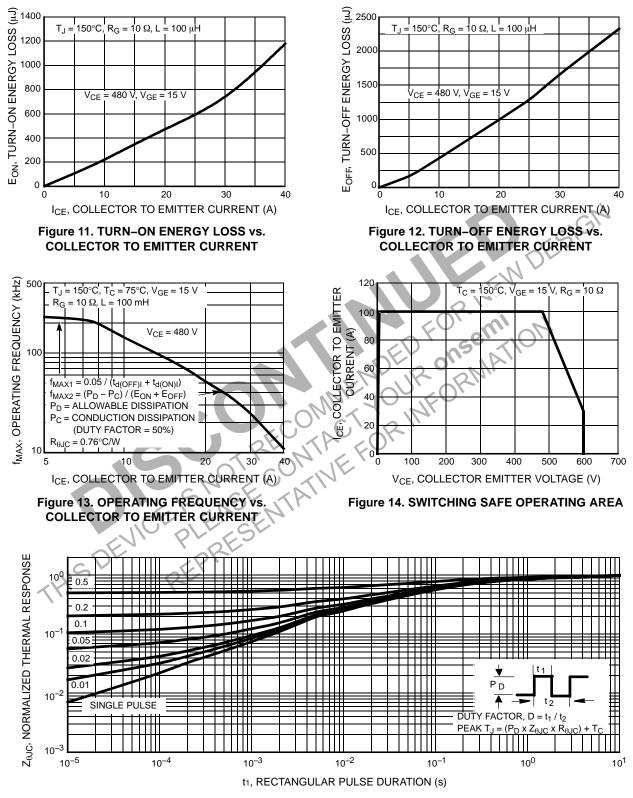
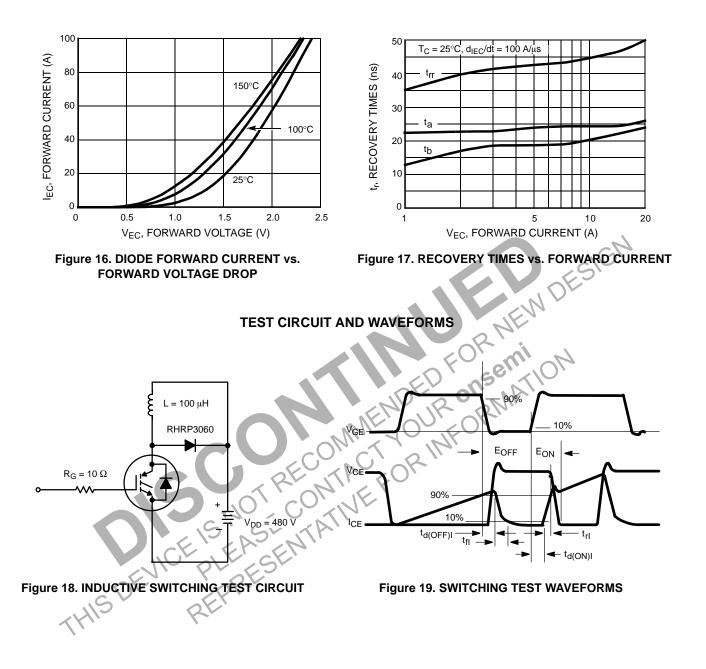


Figure 15. IGBT NORMALIZED TRANSIENT THERMAL RESPONSE, JUNCTION TO CASE

## TYPICAL PERFORMANCE CURVES (continued)



#### HANDLING PRECAUTIONS FOR IGBTs

Insulated Gate Bipolar Transistors are susceptible to gate–insulation damage by the electrostatic discharge of

energy through the devices. When handling these devices, care should be exercised to assure that the static charge built in the handler's body capacitance is not discharged through the device. With proper handling and discharge procedures, however, IGBTs are currently being extensively used in production by numerous equipment manufacturers in military, industrial and consumer applications, with virtually no damage problems due to electrostatic discharge. IGBTs can be handled safely if the following basic precautions are taken:

- Prior to assembly into a circuit, all leads should be kept shorted together either by the use of metal shorting springs or by the insertion into conductive material such as "ECCOSORBD<sup>™</sup> LD26" or equivalent.
- 2. When devices are removed by hand from their carriers, the hand being used should be grounded by any suitable means for example, with a metallic wristband.
- 3. Tips of soldering irons should be grounded.
- 4. 1. Devices should never be inserted into or removed from circuits with power on.
- 5. *Gate Voltage Rating* Never exceed the gate–voltage rating of  $V_{GEM}$ . Exceeding the rated  $V_{GE}$  can result in permanent damage to the oxide layer in the gate region.
- 6. Gate Termination The gates of these devices are essentially capacitors. Circuits that leave the gate open– circuited or floating should be avoided. These conditions can result in turn–on of the device due to voltage buildup on the input capacitor due to leakage currents or pickup.
- 7. *Gate Protection* These devices do not have an internal monolithic zener diode from gate to emitter. If gate protection is required an external zener is recommended.

#### **OPERATING FREQUENCY INFORMATION**

Operating frequency information for a typical device (Figure 13) is presented as a guide for estimating device performance for a specific application. Other typical frequency vs collector current ( $I_{CE}$ ) plots are possible using the information shown for a typical unit in Figures 4, 7, 8, 11 and 12. The operating frequency plot (Figure 13) of a typical device shows  $f_{MAX1}$  or  $f_{MAX2}$  whichever is smaller at each point. The information is based on measurements of a typical device and is bounded by the maximum rated junction temperature.

 $f_{MAX1}$  is defined by  $f_{MAX1} = 0.05$  /  $(t_{d(OFF)I}\ t_{d(ON)I}).$  Deadtime (the denominator) has been arbitrarily held to 10% of the on– state time for a 50% duty factor. Other definitions are possible.  $t_{d(OFF)I}\ and\ t_{d(ON)I}$  are defined in Figure 19.

Device turn–off delay can establish an additional frequency limiting condition for an application other than  $T_{JM}$ .  $t_{d(OFF)I}$  is important when controlling output ripple under a lightly loaded condition.

 $f_{MAX2}$  is defined by  $f_{MAX2}$  =  $(P_D - P_C) / (E_{OFF} + E_{ON})$ . The allowable dissipation  $(P_D)$  is defined by  $P_D$  =  $(T_{JM} - T_C) / R_{\theta JC}$ . The sum of device switching and conduction losses must not exceed  $P_D$ . A 50% duty factor was used (Figure 13) and the conduction losses  $(P_C)$  are approximated by  $P_C = (V_{CE} \, x \, I_{CE}) / 2$ .

 $E_{ON}$  and  $E_{OFF}$  are defined in the switching waveforms shown in Figure 19.  $E_{ON}$  is the integral of the instantaneous power loss ( $I_{CE} \times V_{CE}$ ) during turn–on and  $E_{OFF}$  is the integral of the instantaneous power loss during turn–off. All tail losses are included in the calculation for  $E_{OFF}$ ; i.e. the collector current equals zero ( $I_{CE} = 0$ ).

#### ORDERING INFORMATION

Part Number	Package	Brand	Shipping	
HGTG20N60B3D	TO-247	G20N60B3D	450 Units / Tube	

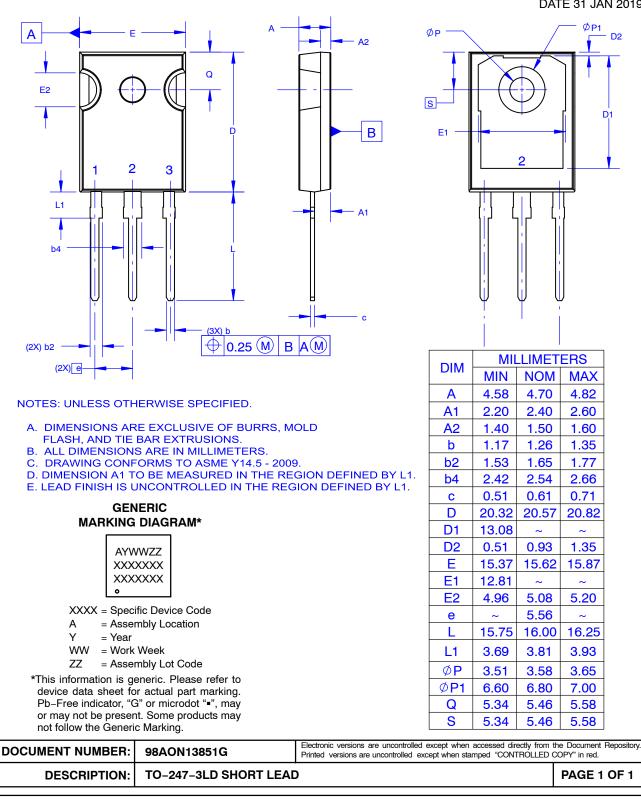
NOTE: When ordering, use the entire part number.

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TO-247-3LD SHORT LEAD CASE 340CK **ISSUE A** 

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